US00D867183S

(12) United States Design Patent

Nasu

(10) **Patent No.: US D867,183 S**

(45) **Date of Patent: ** Nov. 19, 2019**

---

(54) **PROBE PIN**

(71) Applicant: **Kabushiki Kaisha Nihon Micronics**, Tokyo (JP)

(72) Inventor: **Mika Nasu**, Tokyo (JP)

(73) Assignee: **Kabushiki Kaisha Nihon Micronics**, Tokyo (JP)

(**) Term: **15 Years**

(21) Appl. No.: **29/612,176**

(22) Filed: **Jul. 28, 2017**

(30) **Foreign Application Priority Data**

Feb. 10, 2017 (JP) 2017-002475

(51) **LOC (12) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/78**

(58) **Field of Classification Search**
USPC D10/78, 80
CPC G01R 1/06; G01R 1/067; G01R 1/06772; G01R 1/06777; G01R 1/06783; G01R 1/06788; G01R 29/0878
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D397,052 S *	8/1998	Arnoux	D10/80	
D686,098 S *	7/2013	Agar	D10/78	
D769,748 S *	10/2016	Teranishi	D10/78	
D769,749 S *	10/2016	Teranishi	D10/78	
D776,551 S *	1/2017	Teranishi	D10/78	
D776,552 S *	1/2017	Teranishi	D10/78	
2011/0050261 A1*	3/2011	Li	G01R 1/06766	324/754.03
2013/0069669 A1*	3/2013	Mogaveera	G01R 1/06777	324/555
2015/0070040 A1*	3/2015	Treibergs	G01R 1/06722	324/754.11
2015/0369859 A1*	12/2015	Suzuki	G01R 1/06722	324/755.08
2017/0138985 A1*	5/2017	Teranishi	G01R 1/067	

FOREIGN PATENT DOCUMENTS

JP	S000763322	5/1989
KR	20160063284 A	6/2016

* cited by examiner

Primary Examiner — Antoine Duval Davis
(74) *Attorney, Agent, or Firm* — Lorenz & Kopf, LLP

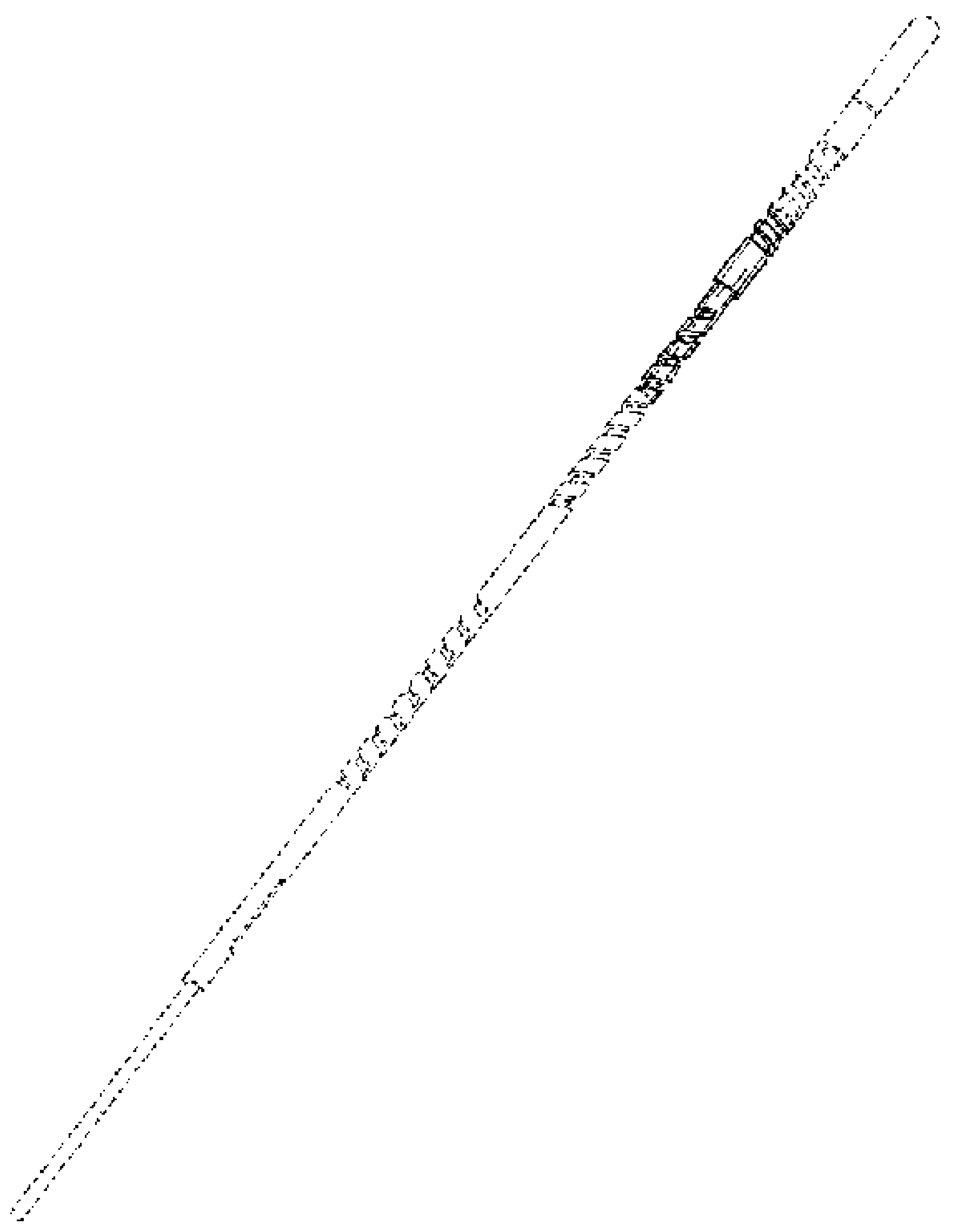
(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a portion of a probe pin, showing the claimed design;
FIG. **2** is a front view of the probe pin;
FIG. **3** is a rear view of the probe pin;
FIG. **4** is a left side view of the probe pin;
FIG. **5** is a right side view of the probe pin;
FIG. **6** is a top plan view of the probe pin;
FIG. **7** is a bottom plan view of the probe pin;
FIG. **8** is an enlarged view of the section of the probe pin identified by the reference Nos. **8**-**8** in FIG. **2**; and,
FIG. **9** is an enlarged left side view of the probe pin.
The broken lines shown in the figures represent portions of the probe pin that form no part of the claimed design. The line-dot broken lines indicate boundary lines between the claimed portions and the disclaimed portions, and are for illustration only and form no part of the claimed design.

1 Claim, 3 Drawing Sheets



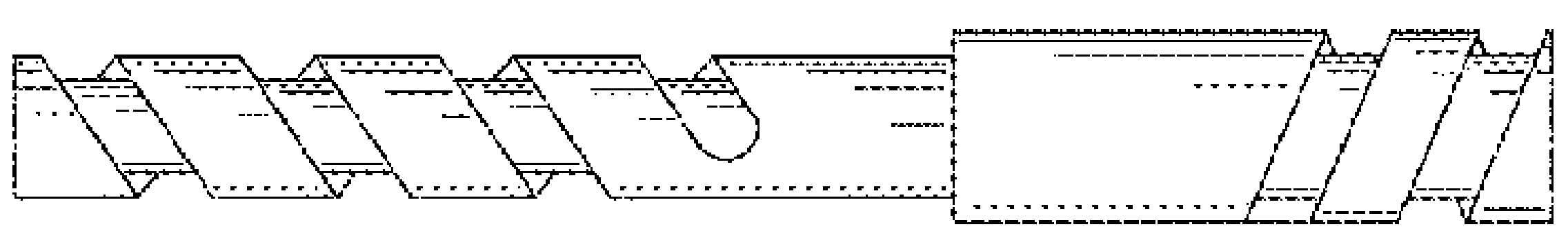


FIG.1

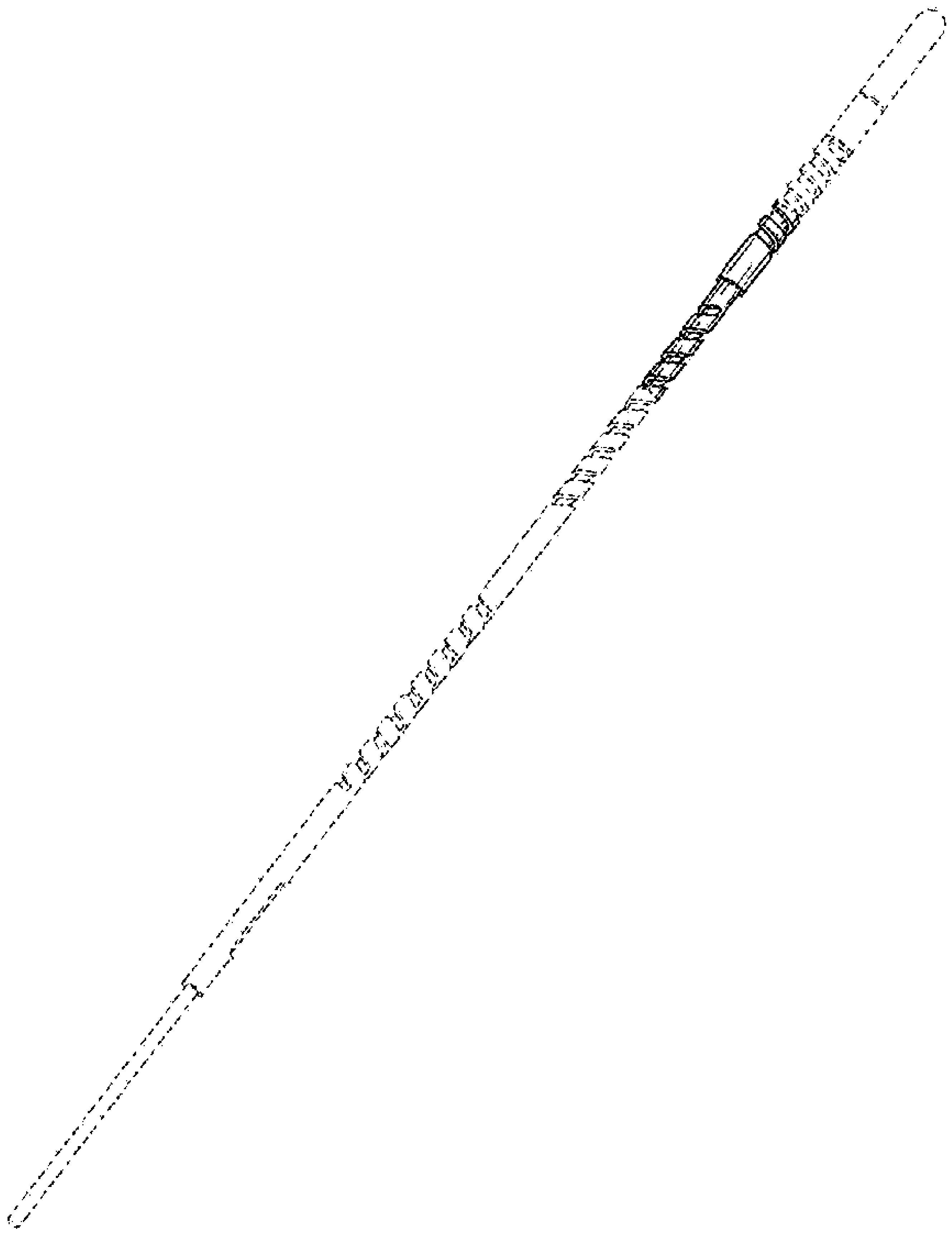


FIG.2

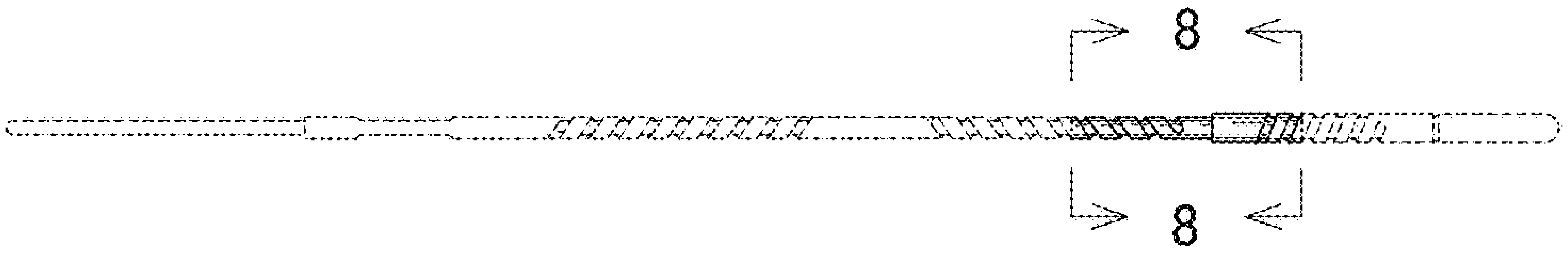


FIG.3

FIG.4

FIG.5

FIG.6

FIG.7

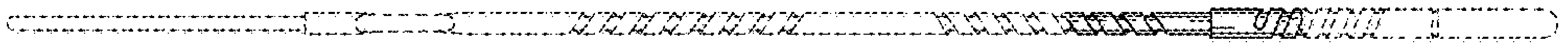


FIG.8

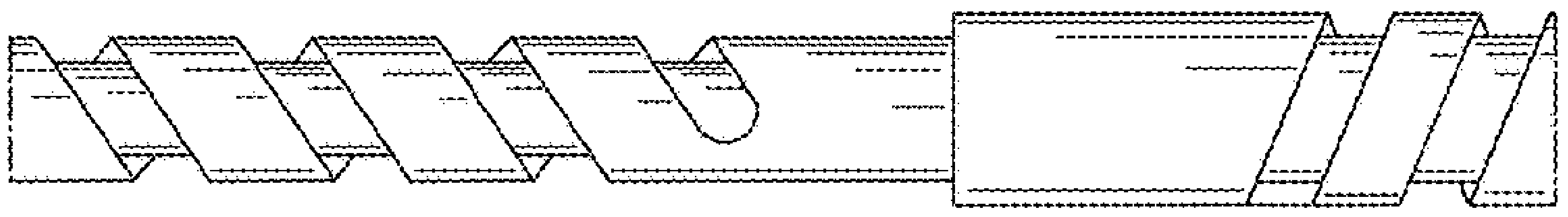


FIG.9